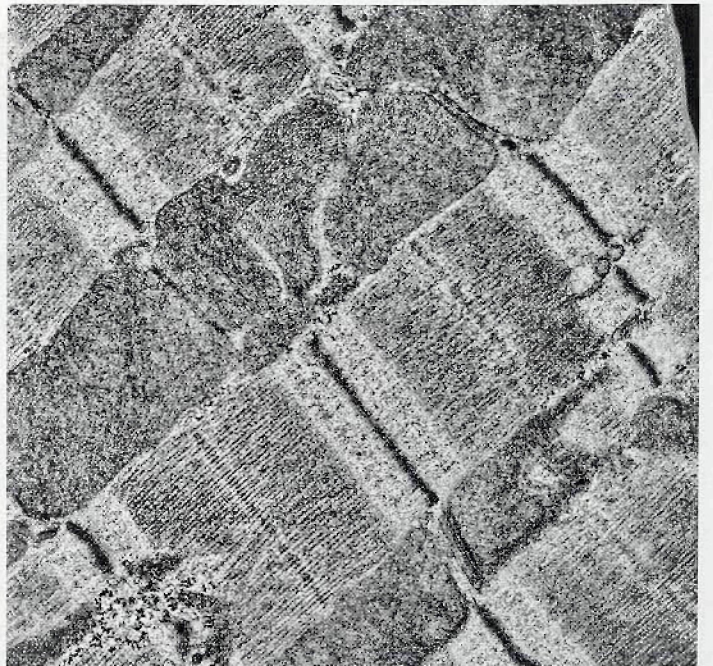
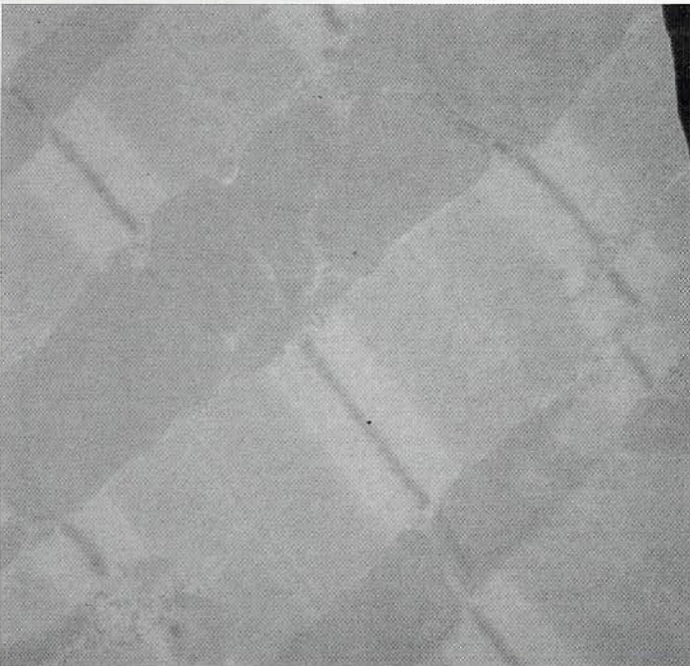
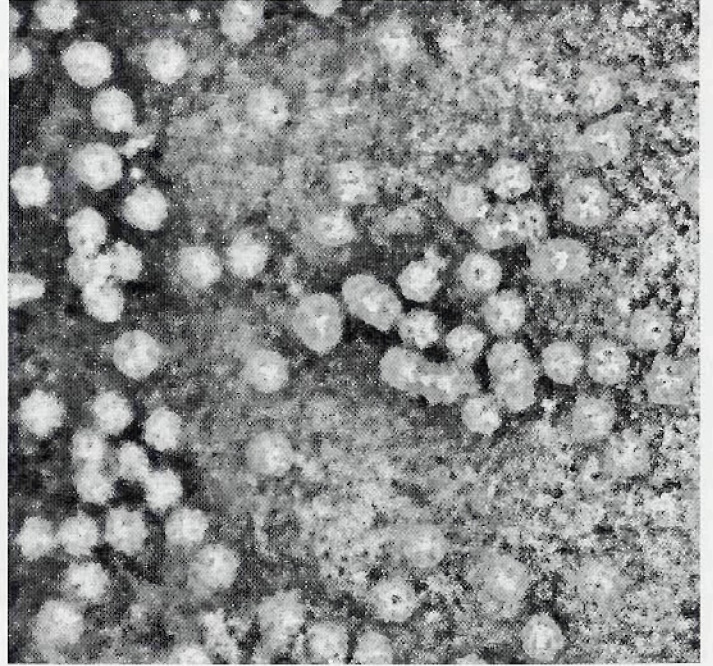
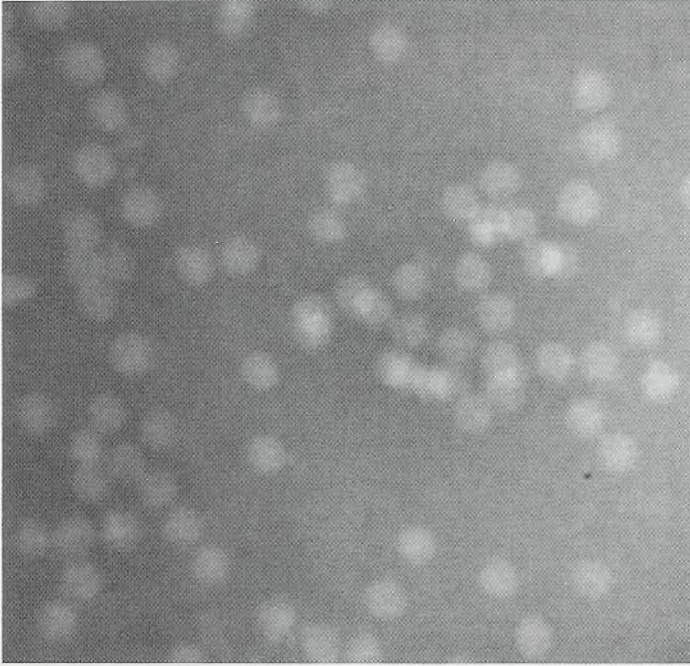


# MICROSCOPY TODAY

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And the  
Happiest of New Years

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**Front Page Image**  
**Digital TEM CCD Camera Data Enhanced with the new PiXISION Imaging**  
**Technique**

These images are before and after examples of images that have been enhanced with the new PiXISION system which is distributed by JEOL USA, Inc. PiXISION displays digital precision image data at any contrast resolution mathematically calculated from the differential hysteresis properties of the intensity distribution within the image. These TEM data were acquired using a JEOL JEM-1210 with a CCD camera at 1K x 1K x 8-bit and reveal the extraordinarily high contrast resolution of the instrument that is not visible in the pure data images. The top images are a negatively stained virus preparation (300,000X original and 2X digitally enlarged) and show capsid substructures in most of the small (30 nm) particles. The bottom images are an unstained Epon section of striated muscle and provide most of the fine structural details which are otherwise only seen after staining. Each image was enhanced in less than 12 seconds. Circle Reader Inquiry # 25

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Don Grimes, Editor

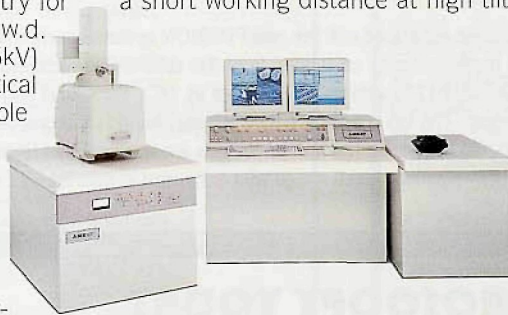
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